## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Ä	US-6,807,668 b2	10-2004	Stern et al.	719/329
*	В	US-5,586,025	12-1996	Tsuji et al.	715/500
*	C	US-6,560,608 b1	05-2003	Tomm et al.	707/102
*	D	US-6,212,577 b1	04-2001	Stern et al.	719/329
*	E	US-2003/0135476 A1	07-2003	Holland et al.	706/47
*	F	US-2004/0027382	02-2004	Kuehn et al.	345/769
*	G	US-2004/0181753	09-2004	Michaelides, Phyllis J.	715/523
*	Н	US-5,283,856	02-1994	Gross et al.	706/47
*	-	US-5,579,521	11-1996	Shearer et al.	719/329
*	J	US-6,324,498	11-2001	Wajda, Wieslawa	703/25
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				-	
	0				•	
	Р					
	Q					
	R					
	s					
	Т					_

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.